

# **TLE94004EP**



### Features

- Four half bridge power outputs
- Very low power consumption in sleep mode
- 3.3V / 5V compatible inputs with hysteresis
- All outputs with overload and short circuit protection
- Direct interface for control and diagnosis
- Overtemperature protection
- Over- and Undervoltage lockout
- Cross-current protection

#### **Potential applications**

- HVAC Flap DC motors
- Monostable and bistable relays
- Side mirror x-y adjustment
- Voltage controlled bipolar stepper motors

## **Product validation**

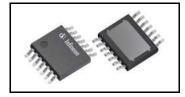
Qualified for Automotive Applications. Product Validation according to AEC-Q100

# Description

The TLE94004EP is a protected quad half-bridge driver designed especially for automotive motion control applications such as Heating, Ventilation and Air Conditioning (HVAC) flap DC motor control. It is part of a larger family offering half-bridge drivers from three outputs to twelve outputs with direct interface or SPI interface.

The half bridge drivers are designed to drive DC motor loads in sequential or parallel operation. Operation modes forward (cw), reverse (ccw), brake and high impedance are controlled from a direct interface. It offers diagnosis features such as short circuit, power supply failure and overtemperature detection. In combination with its low quiescent current, this device is attractive among others for automotive applications. The small fine pitch exposed pad package, PG-TSDSO-14, provides good thermal performance and reduces PCB-board space and costs.

Туре	Package	Marking
TLE94004EP	PG-TSDSO-14	TLE94004





#### Table 1 Product Summary

Operating Voltage	Vs	5.5 20 V
Logic Supply Voltage	V <sub>DD</sub>	3.0 5.5 V
Maximum Supply Voltage for Load Dump Protection	V <sub>S(LD)</sub>	40 V
Minimum Overcurrent Threshold	I <sub>SD</sub>	0.9 A
Maximum On-State Path Resistance at $T_j = 150^{\circ}C$	R <sub>DSON(total)_HSx+LSy</sub>	1.8 + 1.8 Ω
Typical Quiescent Current at T <sub>j</sub> = 85°C	I <sub>SQ</sub>	0.1 μΑ



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**Pin Configuration** 

# **1** Pin Configuration

#### 1.1 Pin Assignment

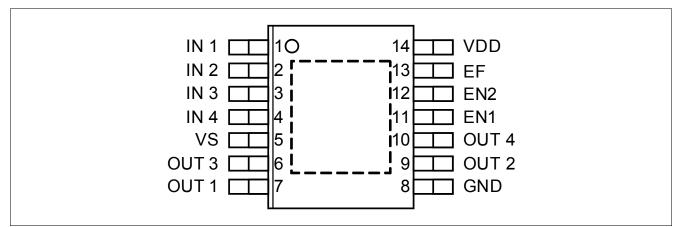


Figure 1	Pin Configuration TLE94004EP with direct interface
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#### 1.2 Pin Definitions and Functions

Pin	Symbol	Function			
1	IN 1	Direct input control for power half-bridge 1			
2	IN 2 Direct input control for power half-bridge 2				
3	IN 3 Direct input control for power half-bridge 3				
4	IN 4	Direct input control for power half-bridge 4			
5	VS	Main supply voltage for power half bridges.			
6	OUT 3	Power half-bridge 3			
7	OUT 1	Power half-bridge 1			
8	GND	Ground			
9	OUT 2	Power half-bridge 2			
10	OUT 4	Power half-bridge 4			
11	EN1	Enable input for Half-bridges 1/2 with internal pull-down			
12	EN2	Enable input for Half-bridges 3/4 with internal pull-down			
13	EF	Error Flag			
14	VDD	Logic supply voltage			
EDP	-	Exposed Die Pad; For cooling and EMC purposes only - not usable as electrical ground. Electrical ground must be provided by pins 8. <sup>1)</sup>			

1) The exposed die pad at the bottom of the package allows better heat dissipation from the device via the PCB. The exposed pad (EP) must be either left open or connected to GND. It is recommended to connect EP to GND for best EMC and thermal performance.



#### Block Diagram

# 2 Block Diagram

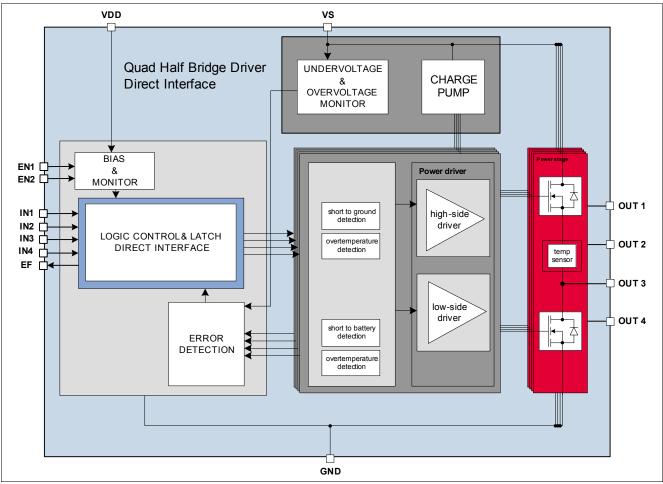


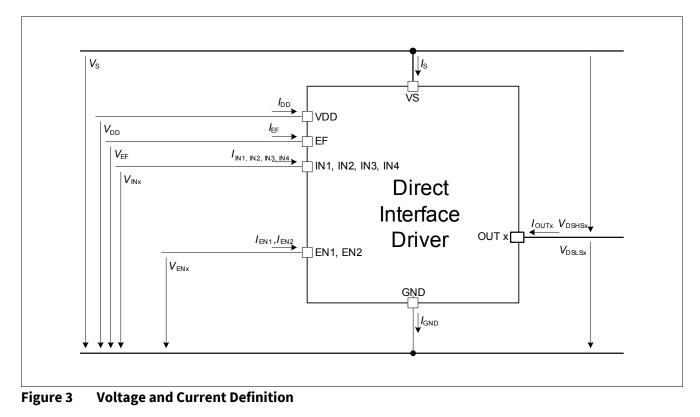
Figure 2 Block Diagram TLE94004EP (Direct Interface)



#### **Block Diagram**

#### 2.1 Voltage and current definition

Figure 3 shows terms used in this datasheet, with associated convention for positive values.





# 3 General Product Characteristics

#### 3.1 Absolute Maximum Ratings

#### Table 2 Absolute Maximum Ratings<sup>1)</sup> $T_i = -40^{\circ}$ C to +150°C

Parameter	Symbol	Values			Unit	Note or	Number	
		Min.	Тур.	Max.		<b>Test Condition</b>		
Voltages	1							
Supply voltage	Vs	-0.3	-	40	V		P_4.1.1	
Supply Voltage Slew Rate	dV₅/dt	-	-	10	V/µs	V <sub>s</sub> increasing and decreasing <sup>1)</sup>	P_4.2.2	
Power half-bridge output voltage	V <sub>OUT</sub>	-0.3	_	40	V	0 V < V <sub>OUT</sub> < V <sub>S</sub>	P_4.1.2	
Logic supply voltage	V <sub>DD</sub>	-0.3	_	5.5	V	$0 V < V_{\rm S} < 40 V$	P_4.1.3	
Logic input voltages (EN1, EN2, IN1, IN2, IN3, IN4)	V <sub>ENn</sub> , V <sub>INn</sub>	-0.3	-	VDD	V	$0 V < V_{S} < 40 V$ $0 V < V_{DD} < 5.5 V$	P_4.1.16	
Logic output voltage (EF)	V <sub>EF</sub>	-0.3	-	VDD	V	$0 V < V_{S} < 40 V$ $0 V < V_{DD} < 5.5 V$	P_4.1.17	
Currents	1							
Continuous Supply Current for V <sub>s</sub>	I <sub>s</sub>	0	-	2.0	А	-	P_4.1.20	
Current per GND pin	I <sub>GND</sub>	0	-	2.0	А	-	P_4.1.14	
Output Currents	I <sub>OUT</sub>	-2.0	-	2.0	А	-	P_4.1.15	
Temperatures								
Junction temperature	T <sub>j</sub>	-40	-	150	°C	-	P_4.1.8	
Storage temperature	T <sub>stg</sub>	-50	-	150	°C	-	P_4.1.9	
ESD Susceptibility								
ESD susceptibility OUTn and VS pins versus GND. All other pins grounded.	V <sub>ESD</sub>	-4	-	4	kV	JEDEC HBM <sup>1)2)</sup>	P_4.1.10	
ESD susceptibility all pins	V <sub>ESD</sub>	-2	-	2	kV	JEDEC HBM <sup>1)2)</sup>	P_4.1.11	
ESD susceptibility all pins	V <sub>ESD</sub>	-500	-	500	V	CDM <sup>1)3)</sup>	P_4.1.12	
ESD susceptibility corner pins	V <sub>ESD</sub>	-750	-	750	V	CDM <sup>1)3)</sup>	P_4.1.13	

1) Not subject to production test, specified by design

2) ESD susceptibility, "JEDEC HBM" according to ANSI/ ESDA/ JEDEC JS001 (1.5 k $\Omega$ , 100pF)

3) ESD susceptibility, Charged Device Model "CDM" according JEDEC JESD22-C101

#### Notes

- 1. Stresses above the ones listed here may cause permanent damage to the device. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.
- 2. Integrated protection functions are designed to prevent IC destruction under fault conditions described in the data sheet. Fault conditions are considered as "outside" normal operating range. Protection functions are not designed for continuous repetitive operation.



#### 3.2 Functional Range

#### Table 3Functional Range

Parameter	Symbol	Values			Unit	Note or	Number
		Min.	Тур.	Max.		<b>Test Condition</b>	
Supply voltage range for normal operation	V <sub>S(nor)</sub>	5.5	-	20	V	-	P_4.2.1
Logic supply voltage range for normal operation	V <sub>DD</sub>	3.0	-	5.5	V	-	P_4.2.3
Logic input voltages (EN1, EN2, IN1, IN2, IN3, IN4)	V <sub>INn</sub> , V <sub>ENn</sub>	-0.3	-	5.5	V	-	P_4.2.6
Junction temperature	Tj	-40	-	150	°C		P_4.2.5

*Note:* Within the normal functional range the IC operates as described in the circuit description. The electrical characteristics are specified within the conditions given in the related electrical characteristics table.



#### 3.3 Thermal Resistance

Parameter	Symbol		Values	5	Unit	Note or Test Condition	Number
		Min.	Тур.	Max.			
Junction to Case, $T_A = -40^{\circ}$ C	R <sub>thjC_cold</sub>	-	14	-	K/W	1)	
Junction to Case, $T_A = 85^{\circ}C$	R <sub>thjC_hot</sub>	-	17	-	K/W	1)	
Junction to ambient, $T_A = -40^{\circ}C$ (1s0p, minimal footprint)	R <sub>thjA_cold_</sub>	-	126	-	K/W	1) 2)	
Junction to ambient, $T_A = 85^{\circ}C$ (1s0p, minimal footprint)	R <sub>thjA_hot_m</sub>	-	134	-	K/W	1) 2)	
Junction to ambient, $T_A = -40^{\circ}$ C (1s0p, 300mm2 Cu)	R <sub>thjA_cold_3</sub>	-	69	-	K/W	1) 3)	
Junction to ambient, $T_A = 85^{\circ}C$ (1s0p, 300mm2 Cu)	R <sub>thjA_hot_30</sub>	-	81	-	K/W	1) 3)	
Junction to ambient, $T_A = -40$ °C (1s0p, 600mm2 Cu)	R <sub>thjA_cold_6</sub>	-	67	-	K/W	1) 4)	
Junction to ambient, $T_A = 85^{\circ}C$ (1s0p, 600mm2 Cu)	R <sub>thjA_hot_60</sub>	-	79	-	K/W	1) 4)	
Junction to ambient, $T_A = -40^{\circ}C$ (2s2p)	R <sub>thjA_cold_2</sub>	-	53	-	K/W	1) 5)	
Junction to ambient, <i>T</i> <sub>A</sub> = 85°C (2s2p)	R <sub>thjA_hot_2s</sub>	-	67	-	K/W	1) 5)	

#### Table 4 Thermal Resistance TLE94004EP

1) Not subject to production test, specified by design.

 Specified R<sub>thJA</sub> value is according to JEDEC JESD51-2, -3 at natural convection on FR4 1s0p board; The product (chip + package) was simulated on a 76.2 x 114.3 x 1.5mm board with minimal footprint copper area and 35µm thickness. Ta = -40°C, each channel dissipates 0.2W. Ta = 85°C, each channel dissipates 0.135W.

- Specified R<sub>thJA</sub> value is according to JEDEC JESD51-2, -3 at natural convection on FR4 1s0p board; The product (chip + package) was simulated on a 76.2 x 114.3 x 1.5mm board with additional cooling of 300mm2 copper area and 35μm thickness. Ta = -40°C, each channel dissipates 0.2W. Ta = 85°C, each channel dissipates 0.135W.
- 4) Specified R<sub>thJA</sub> value is according to JEDEC JESD51-2, -3 at natural convection on FR4 1s0p board; The product (chip + package) was simulated on a 76.2 x 114.3 x 1.5mm board with additional cooling of 600mm2 copper area and 35μm thickness. Ta = -40°C, each channel dissipates 0.2W. Ta = 85°C, each channel dissipates 0.135W.
- 5) Specified *R*<sub>thJA</sub> value is according to JEDEC JESD51-2, -3 at natural convection on FR4 2s2p board; The product (chip + package) was simulated on a 76.2 x 114.3 x 1.5mm board with two inner copper layers (4 x 35μm Cu). Ta = -40°C, each channel dissipates 0.2W. Ta = 85°C, each channel dissipates 0.135W.



#### 3.4 Electrical Characteristics

# Table 5Electrical Characteristics, $V_s = 5.5 V \text{ to } 20 V$ , $V_{DD} = 3.0V \text{ to } 5.5V$ , $T_j = -40^{\circ}\text{C}$ to $+150^{\circ}\text{C}$ , EN1= HIGH<br/>and EN2= HIGH, $I_{OUTn} = 0 \text{ A}$ ; Typical values refer to $V_{DD} = 5.0 V$ , $V_s = 13.5 V$ and $T_J = 25^{\circ}\text{C}$ unless<br/>otherwise specified; all voltages with respect to ground, positive current flowing into pin<br/>(unless otherwise specified)

Parameter	Symbol	Values			Unit	Note or	Number
		Min. Typ. Max.		Test Condition			
Current Consumption, EN1 = E	N2 = GND						
Supply Quiescent current	I <sub>SQ</sub>	-	0.1	2	μA	$-40^{\circ}\text{C} \le T_{j} \le 85^{\circ}\text{C}$	P_4.4.1
Logic supply quiescent current	I <sub>DD_Q</sub>	-	0.1	1	μA	$-40^{\circ}C \le T_j \le 85^{\circ}C$	P_4.4.2
Total quiescent current	$I_{SQ} + I_{DD_Q}$	-	0.6	3	μA	$-40^{\circ}C \le T_j \le 85^{\circ}C$	P_4.4.3
Current Consumption, EN=HIG	ίΗ						
Supply current	I <sub>S_HSON</sub>	-	1.5	3	mA	All high-sides ON <sup>1)2)</sup>	P_4.4.101
Logic supply current	I <sub>DD</sub>	-	0.6	2.5	mA		P_4.4.5
Over- and Undervoltage Locko	out						
Undervoltage Switch ON voltage threshold	V <sub>UV ON</sub>	4.4	4.90	5.3	V	V <sub>s</sub> increasing	P_4.4.8
Undervoltage Switch OFF voltage threshold	V <sub>UV OFF</sub>	4	4.50	4.9	V	V <sub>S</sub> decreasing	P_4.4.9
Undervoltage Switch ON/OFF hysteresis	V <sub>UV HY</sub>	-	0.40	-	V	$V_{\rm UV  ON}$ - $V_{\rm UV  OFF}$ <sup>2)</sup>	P_4.4.10
Overvoltage Switch OFF voltage threshold	V <sub>OV OFF</sub>	21	23	25	V	V <sub>s</sub> increasing	P_4.4.11
Overvoltage Switch ON voltage threshold	V <sub>OV ON</sub>	20	22	24	V	V <sub>s</sub> decreasing	P_4.4.12
Overvoltage Switch ON/OFF hysteresis	V <sub>OV HY</sub>	-	1	-	V	$V_{\rm OVOFF}$ - $V_{\rm OVON}^{2)}$	P_4.4.13
V <sub>DD</sub> Power-On-Reset	V <sub>DD POR</sub>	2.40	2.63	2.90	V	V <sub>DD</sub> increasing	P_4.4.14
V <sub>DD</sub> Power-Off-Reset	V <sub>DD POffR</sub>	2.35	2.57	2.85	V	V <sub>DD</sub> decreasing	P_4.4.15
V <sub>DD</sub> Power ON/OFF hysteresis	V <sub>DD POR HY</sub>	_	0.06	-	V	$V_{\rm DD POR} - V_{\rm DD POffR}^{2)}$	P_4.4.98
Static Drain-source ON-Resista		de or L	.ow-Sid	e)			
High-Side or Low-Side R <sub>DSON</sub> (all outputs)	R <sub>DSON_HB_25C</sub>	-	825	1200	mΩ	I <sub>OUT</sub> = ±0.5 A; T <sub>i</sub> = 25 °C	P_4.4.16
High-Side or Low-Side R <sub>DSON</sub> (all outputs)	R <sub>DSON_HB_150</sub>	-	1350	1800	mΩ	$I_{OUT} = \pm 0.5 \text{ A};$ $T_{i} = 150 \text{ °C}$	P_4.4.17
Output Protection and Diagno		de (HS)	chann	els of h	alf-brid	ge output	1
HS Overcurrent Shutdown Threshold	I <sub>SD_HS</sub>	-1.5	-1.2	-0.9	A	See Figure 6	P_4.4.20
Difference between shutdown and limit current	I <sub>lim_hs</sub> - I <sub>sd_hs</sub>	-1.2	-0.6	0	A	$ I_{\text{LIM}_{\text{HS}}}  \ge  I_{\text{SD}_{\text{HS}}} $ See <b>Figure 6</b>	P_4.4.21



Table 5Electrical Characteristics,  $V_s = 5.5 V to 20 V$ ,  $V_{DD} = 3.0V to 5.5V$ ,  $T_j = -40^{\circ}C to +150^{\circ}C$ , EN1= HIGH<br/>and EN2= HIGH,  $I_{OUTn} = 0 A$ ; Typical values refer to  $V_{DD} = 5.0 V$ ,  $V_s = 13.5 V$  and  $T_J = 25^{\circ}C$  unless<br/>otherwise specified; all voltages with respect to ground, positive current flowing into pin<br/>(unless otherwise specified) (cont'd)

Parameter	Symbol		Values			Note or	Number
		Min.	Тур.	Max.		<b>Test Condition</b>	
Overcurrent Shutdown filter time	t <sub>dSD_HS</sub>	15	19	23	μs	2)	P_4.4.22
Output Protection and Diagno	sis of low-s	ide (LS)	channe	ls of ha	lf-bridg	e output	
LS Overcurrent Shutdown Threshold	I <sub>SD_LS</sub>	0.9	1.2	1.5	A	See Figure 7	P_4.4.27
Difference between shutdown and limit current	I <sub>lim_ls</sub> - I <sub>SD_ls</sub>	0	0.6	1.2	A	<sup>2)</sup> $I_{\text{LIM}_{\text{LS}}} \ge I_{\text{SD}_{\text{LS}}}$ Figure 7	P_4.4.28
Overcurrent Shutdown filter time	t <sub>dSD_LS</sub>	15	19	23	μs	2)	P_4.4.29
Outputs OUT(1n) leakage cu	irrent	<b>I</b>		4		-	
HS leakage current in off state	I <sub>QLHn_NOR</sub>	-2	-0.5	-	μA	V <sub>OUTn</sub> =0V; OUT1/2: EN1=GND, EN2=High; OUT3/4: EN1=High,EN2=GN D	P_4.4.32
HS leakage current in off state	I <sub>QLHn_SLE</sub>	-2	-0.5	-	μΑ	V <sub>OUTn</sub> = 0V; EN1 = EN2 =GND	P_4.4.33
LS Leakage current in off state	I <sub>QLLn_NOR</sub>	-	0.5	2	μA	V <sub>OUTn</sub> = V <sub>S</sub> ; OUT1/2: EN1=GND, EN2=High; OUT3/4: EN1=High,EN2=GN D	P_4.4.34
LS Leakage current in off state	I <sub>QLLn_SLE</sub>	-	0.5	2	μA	$V_{OUTn} = V_S$ ; EN1 = EN2 =GND	P_4.4.35
Output Switching Times. See I	Figure 8 and	Figure 9	Э.			•	- <u>+</u>
Slew rate of high-side and low- side outputs	d <sub>vout</sub> / dt	0.1	0.45	0.75	V/µs	Resistive load = $100\Omega; V_{\rm S}$ =13.5V <sup>3)</sup>	P_4.4.36
Output delay time high side driver on	t <sub>donh</sub>	5	20	35	μs	Resistive load = 100Ω to GND	P_4.4.37
Output delay time high side driver off	t <sub>doffh</sub>	15	45	75	μs	Resistive load = 100Ω to GND	P_4.4.38
Output delay time low side driver on	t <sub>donl</sub>	5	20	35	μs	Resistive load = 100Ω to VS	P_4.4.39
Output delay time low side driver off	t <sub>dOFFL</sub>	15	45	75	μs	Resistive load = 100Ω to VS	P_4.4.40
Cross current protection time, high to low	t <sub>DHL</sub>	100	130	160	μs	Resistive load = $100\Omega^{2}$	P_4.4.41
Cross current protection time, low to high	t <sub>DLH</sub>	100	130	160	μs	Resistive load = $100\Omega^{2}$	P_4.4.42



Table 5Electrical Characteristics,  $V_s = 5.5 V to 20 V$ ,  $V_{DD} = 3.0V to 5.5V$ ,  $T_j = -40^{\circ}C to +150^{\circ}C$ , EN1= HIGH<br/>and EN2= HIGH,  $I_{OUTn} = 0 A$ ; Typical values refer to  $V_{DD} = 5.0 V$ ,  $V_s = 13.5 V$  and  $T_J = 25^{\circ}C$  unless<br/>otherwise specified; all voltages with respect to ground, positive current flowing into pin<br/>(unless otherwise specified) (cont'd)

Parameter	Symbol		Value	S	Unit	Note or	Number
		Min.	Тур.	Max.	_	<b>Test Condition</b>	
Input Interface: Logic Inputs E	N1, EN2			*		•	- <u>!</u>
Set up time after sleep mode	t <sub>SET_DI</sub>	-	-	150	μs	<sup>2)</sup> See Figure 5	P_4.4.49
High-input voltage	V <sub>ENH</sub>	0.7 * V <sub>DD</sub>	-	V <sub>DD</sub>	V	-	P_4.4.43
Low-input voltage	V <sub>enl</sub>	0	-	0.3 * V <sub>DD</sub>	V	-	P_4.4.44
Hysteresis of input voltage	V <sub>ENHY</sub>	-	500	-	mV	2)	P_4.4.45
Pull down resistor	R <sub>PD_EN</sub>	20	40	70	kΩ	$V_{\rm EN1/2} = 0.2  {\rm x}  V_{\rm DD}$	P_4.4.46
EF reset time	t <sub>ef_reset</sub>	250	-	-	ns	<sup>2)</sup> Set ENx to Low for $t_{\text{EF}_{\text{RESET}}}$ to reset EF	P_4.4.121
Input Interface: Logic Inputs II	N1, IN2, IN3	, IN4					
High input voltage threshold	V <sub>INnH</sub>	0.7 * V <sub>DD</sub>	-	V <sub>DD</sub>	V	-	P_4.4.90
Low input voltage threshold	V <sub>INnL</sub>	0	-	0.3 * V <sub>DD</sub>	V	-	P_4.4.91
Hysteresis of input voltage	V <sub>INnHY</sub>	-	500	-	mV	2)	P_4.4.92
Pull-down resistor	R <sub>PD</sub>	20	40	70	kΩ	-	P_4.4.94
Output Interface: Logic Outpu	t EF		<b>!</b>	*	-+	•	
High output voltage level	V <sub>efh</sub>	V <sub>DD</sub> - 0.4	V <sub>DD</sub> - 0.2	V <sub>DD</sub>	V	I <sub>EFH</sub> = -1.6 mA	P_4.4.88
Low output voltage level	V <sub>EFL</sub>	0	0.2	0.4	V	I <sub>EFL</sub> = 1.6 mA	P_4.4.95
Leakage current	I <sub>eflk</sub>	-1	-	1	μΑ	0V < V <sub>EF</sub> < 5.5V	P_4.4.96
Thermal Shutdown	·			÷	· ·		
Thermal shutdown junction temperature	T <sub>jSD</sub>	160	175	190	°C	See Figure 10 <sup>2)</sup>	P_4.4.81
Thermal comparator hysteresis	T <sub>iHYS</sub>	-	4	-	°C	2)	P_4.4.82

1)  $I_{\rm S HSON}$  does not include the load current

2) Not subject to production test, specified by design

3) Measured for 20% - 80% of  $V_{\rm S}$ .

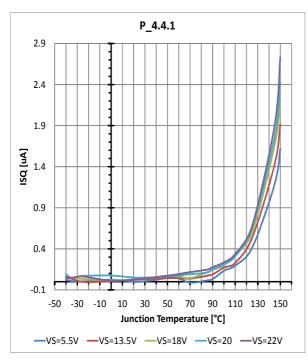


# 4 Characterization results

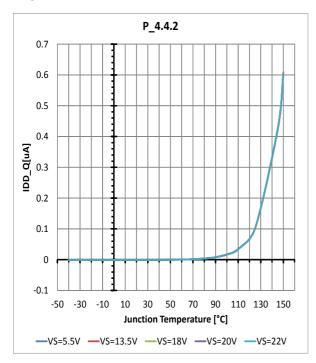
Performed on 5 devices, over operating temperature and nominal/extended supply range.

#### **Typical performance characteristics**

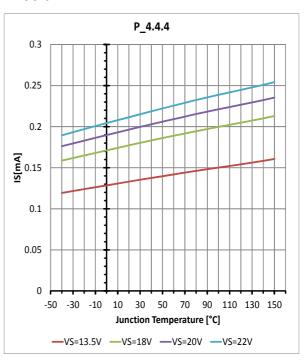
#### Supply quiescent current



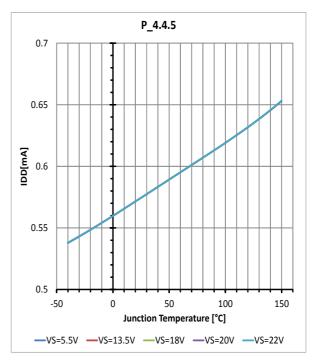
#### Logic supply quiescent current



#### Supply current

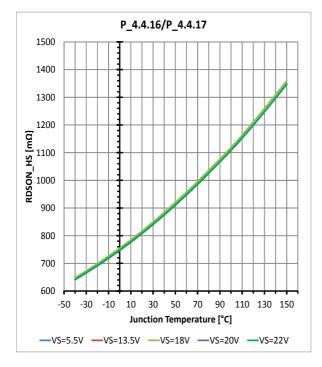


#### Logic supply current



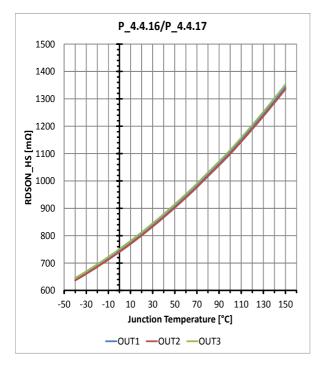






#### HS static Drain-source ON-resistance

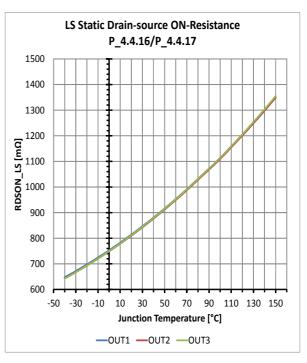
#### HS static drain-source ON-resistance VS = 13.5V and VDD = 5V



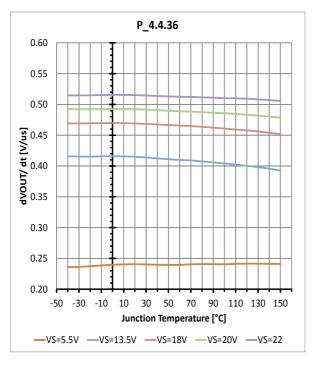
# P\_4.4.16/P\_4.4.17

LS static Drain-source ON-resistance

#### LS static drain-source ON-resistance VS = 13.5V and VDD = 5V

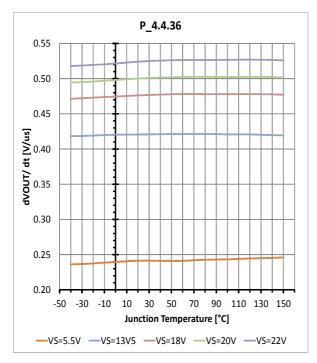






#### Slew rate ON of high-side outputs

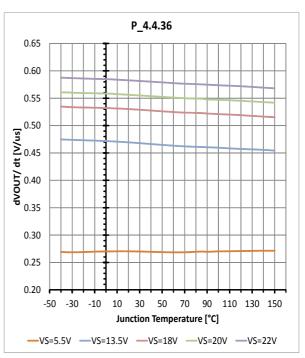
#### Slew rate OFF of high-side outputs



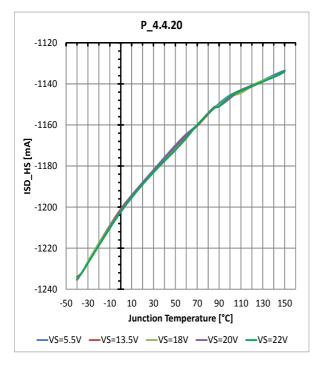
# P\_4.4.36

Slew rate ON of low-side outputs

#### Slew rate OFF of low-side outputs

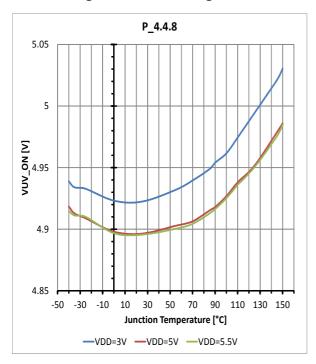


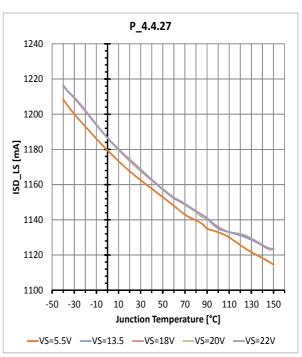




#### HS overcurrent shutdown threshold

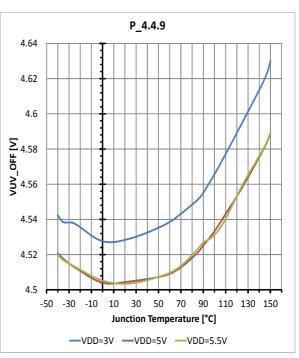
#### Undervoltage switch ON voltage threshold



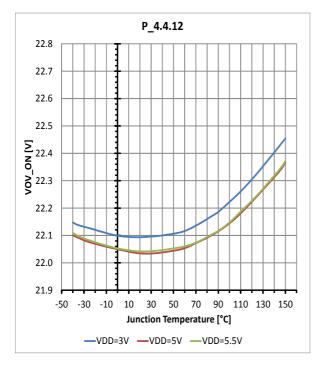


#### LS overcurrent shutdown threshold

Undervoltage switch OFF voltage threshold

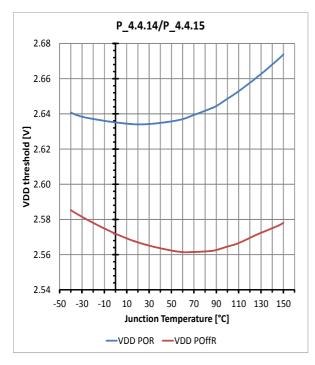


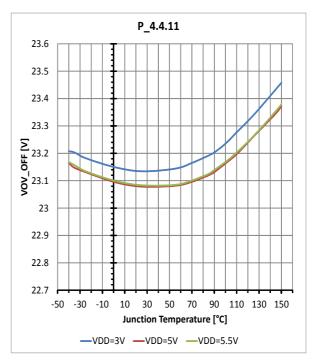




#### Overvoltage switch ON voltage threshold

#### VDD Power-on-reset and VDD Power-off-reset





#### **Overvoltage switch OFF voltage threshold**



#### **General Description**

# 5 General Description

#### 5.1 Power Supply

The TLE94004EP has two power supply inputs,  $V_{\rm S}$  and  $V_{\rm DD}$ . The half bridge outputs are supplied by  $V_{\rm S}$ , which is connected to the 12V automotive supply rail.  $V_{\rm DD}$  is used to supply the I/O buffers and internal voltage regulator of the device.

 $V_{\rm S}$  and  $V_{\rm DD}$  supplies are separated so that information stored in the logic block remains intact in the event of voltage drop outs or disturbances on  $V_{\rm S}$ . The system can therefore continue to operate once  $V_{\rm S}$  has recovered, without having to resend commands to the device.

A rising edge on  $V_{DD}$  crossing  $V_{DD POR}$  triggers an internal Power-On Reset (POR) to initialize the IC at power-on. All data stored internally is deleted, and the outputs are switched off (high impedance).

An electrolytic and 100nF ceramic capacitors are recommended to be placed as close as possible to the  $V_{\rm S}$  supply pin of the device for improved EMC performance in the high and low frequency band. The electrolytic capacitor must be dimensioned to prevent the VS voltage from exceeding the absolute maximum rating. In addition, decoupling capacitors are recommended on the  $V_{\rm DD}$  supply pin.

#### 5.2 Operation modes

#### 5.2.1 Normal mode

The TLE94004EP enters normal mode by setting EN1 or EN2 to High. In normal mode, the charge pump is active and all output transistors can be activated or deactivated according to **Chapter 6.1**.

#### 5.2.2 Sleep mode

The TLE94004EP enters sleep mode by setting the EN1 and EN2 pins to Low. The EN1 and EN2 inputs have an internal pull-down resistor.

In sleep mode, all output transistors are turned off and the logic content is reset. The current consumption is reduced to  $I_{SQ} + I_{DD_Q}$ .

#### 5.3 Reset Behaviour

The following reset triggers have been implemented in the TLE94004EP:

#### V<sub>DD</sub> Undervoltage Reset:

The digital block will be deactivated, the logic contents cleared and the output stages are switched off if  $V_{DD}$  is below the undervoltage threshold,  $V_{DD POffR}$ . The digital block is initialized once  $V_{DD}$  voltage levels is above the undervoltage threshold,  $V_{DD POR}$ .

#### **Reset on EN1/2 pins:**

If the EN1/2 pins are pulled Low, the logic content is reset and the device enters sleep mode.

#### 5.4 Reverse Polarity Protection

The TLE94004EP requires an external reverse polarity protection. During reverse polarity, the free-wheeling diodes across the half bridge output will begin to conduct, causing an undesired current flow ( $I_{RB}$ ) from ground potential to battery and excessive power dissipation across the diodes. As such, a reverse polarity protection diode is recommended (see **Figure 4**).



#### **General Description**

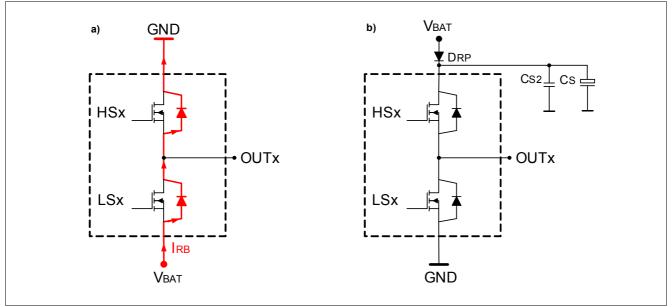


Figure 4 Reverse Polarity Protection



## 6 Half-Bridge Outputs

The half-bridge outputs of the TLE94004EP are intended to drive motor loads. They consist of a total of four DMOS half-bridges, which can be driven either continuously or in PWM via INx pins. The output stages integrated circuits protect the outputs against overcurrent and overtemperature.

#### 6.1 Output Stages

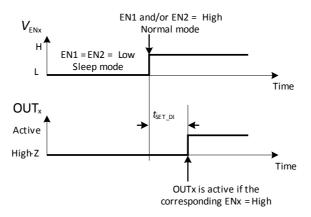
EN1 and EN2 inputs control the state of the device according to **Table 6**.

- When EN1 = 0 and EN2 = 0, the device enters sleep mode with low power consumption and all outputs are OFF (high impedance).
- When EN1=1, HB1 and HB2 are enabled
- When EN2=1, HB3 and HB4 are enabled

EN1	EN2	HB1/2	HB 3/4	Device state
0	0	OFF	OFF	Sleep mode, all outputs are OFF
0	1	OFF	Enabled	Device is in normal mode
1	0	Enabled	OFF	Device is in normal mode
1	1	Enabled	Enabled	Device is in normal mode

Table 6 Device states

*Note:* After the transition from sleep mode to normal mode, the outputs are OFF for a duration t<sub>SET\_DI</sub>.See **Figure 5** 



#### Figure 5 Output setup time after a transition from standby to normal mode

The control inputs consist of CMOS-compatible schmitt-triggers with hysteresis. There are altogether four control inputs, i.e. IN1, IN2, IN3 and IN4 with internal pull-down resistors.

If EN1 = 0, HB1 and HB2 are OFF. If EN1 = 1, HB1 and HB2 are controlled according to Table 7

Table 7 Functional Truth Table for HB1 and HB2
--

EN1	IN1	IN2	HB1	HB2	Mode
0	Х	Х	OFF	OFF	HB1 and HB2 are OFF
1	0	0	L	L	Brake Low

#### **TLE94004EP**



#### Half-Bridge Outputs

EN1	IN1	IN2	HB1	HB2	Mode
1	0	1	L	Н	Motor counter-clockwise
1	1	0	Н	L	Motor clockwise
1	1	1	Н	Н	Brake High

#### Table 7Functional Truth Table for HB1 and HB2

If EN2 = 0, HB3 and HB4 are OFF. If EN2 =1, HB3 and HB4 are controlled according to Table 8

EN2	IN3	IN4	HB3	HB4	Mode
0	Х	Х	OFF	OFF	HB3 and HB4 are OFF
1	0	0	L	L	Brake Low
1	0	1	L	Н	Motor counter-clockwise
1	1	0	Н	L	Motor clockwise
1	1	1	Н	Н	Brake High

#### Table 8Functional Truth table for HB3 and HB4



#### 6.2 Diagnosis Monitoring

The EF pin (push-pull output) reports the following error conditions:

- Overcurrent (OC)
- Overtemperature (OT)
- VS overvoltage and VS undervoltage

EF reports an overcurrent event on HB1/2 only if EN1 = 1. Likewise, EF reports an overcurrent on HB3/4 only if EN2 = 1.

After an overcurrent event is detected on HB1/2, EF is latched to 1, until EN1 = 0.Likewise, after an overcurrent event detected on HB3/4, EF is latched to 1 until EN2 = 0.

EF reports overtemperature or VS overvoltage/undervoltage events if the device is in normal mode (EN1 = 1 or EN2 = 1). The error flag is latched to 1 for these fault conditions until EN1 = 0 and EN2 = 0

10010 0				
EN1	EN2	Error reported by EF pin		
0	0	Not applicable, the device is in sleep mode		
1	0	OC on HB1/2, OT, VS under/overvoltage		
0	1	OC on HB3/4, OT, VS under/overvoltage		
1	1	OC on HB1/2, OC on HB3/4, OT, VS under/overvoltage		

#### Table 9 Error reporting by EF pin

The table below depicts the EF behaviour:

 Table 10
 Error flag behaviour and reset conditions

•		
Fault condition	EF	Reset conditions
No fault	0	-
Overcurrent on HB1 or HB2	1 (latched)	Set EN1 pin to 0 for <b>t<sub>EF_RESET</sub></b>
Overcurrent on HB3 or HB4	1 (latched)	Set EN2 pin to 0 for <b>t<sub>EF_RESET</sub></b>
VS overvoltage	1 (latched)	$V_{\rm S} < V_{\rm OV ON}$ , EN1 = 0 and EN2 = 0 for $t_{\rm EF_RESET}$
VS undervoltage	1 (latched)	$V_{\rm S} > V_{\rm UV ON}$ , EN1 = 0 and EN2 = 0 for $t_{\rm EF\_RESET}$
Overtemperature	1 (latched)	$EN1 = 0$ and $EN2 = 0$ for $t_{EF\_RESET}$

#### 6.3 Protection

This device has embedded protective functions which are designed to prevent the destruction of the device under fault conditions described in this section. Fault conditions are treated as "outside" normal operating range. Protection functions are not designed for continuous repetitive operation.

#### 6.3.1 Short Circuit of Output to Supply or Ground

The high-side switches are protected against short circuits to ground whereas the low-side switches are protected against short circuits to supply.

The high-side and low-side switches will enter into an over-current condition if the current within the switch exceeds the overcurrent shutdown detection threshold,  $I_{SD}$ . Upon detection of the  $I_{SD}$  threshold, an



overcurrent shutdown filter,  $t_{dSD}$  is begun. As the current rises beyond the threshold  $I_{SD}$ , it will be limited by the current limit threshold,  $I_{LIM}$ . Upon expiry of the overcurrent shutdown filter time, the affected power switch is latched off (see **Figure 6** and **Figure 7**) and the EF is set to 1 and latched.

The faulty power switch remains deactivated and EF is latched as long as the corresponding ENx =1.

To resume normal functionality of the power switch (in the event the overcurrent condition disappears or to verify if the failure still exists) the microcontroller shall:

- 1. clear the error flag by setting the corresponding ENx to 0 (see Table 10)
- 2. set the corresponding ENx to 1 in order to re-enable the corresponding half-bridges

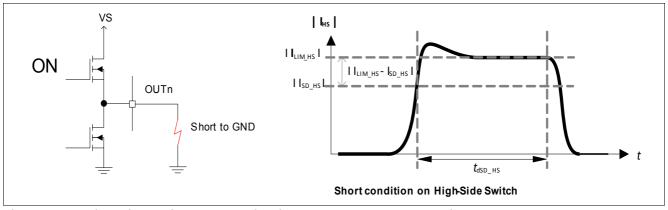


Figure 6 High-Side Switch - Short Circuit and Overcurrent Protection

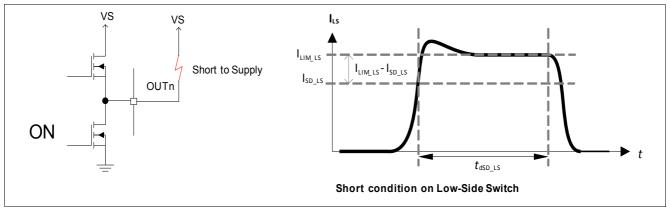


Figure 7 Low-Side Switch - Short Circuit and Overcurrent Protection

#### 6.3.2 Cross-current protection

In bridge configurations the high-side and low-side power transistors are ensured never to be simultaneously "ON" to avoid cross currents. This is achieved by integrating delays in the driver stage of the power outputs to create a dead-time between switching off of one power transistor and switching on of the adjacent power transistor within the half-bridge. The dead times,  $t_{\text{DHL}}$  and  $t_{\text{DLH}}$ , as shown in **Figure 8** case 3 and **Figure 9** case 3, have been specified to ensure that the switching slopes do not overlap with each other. This prevents a cross conduction event.



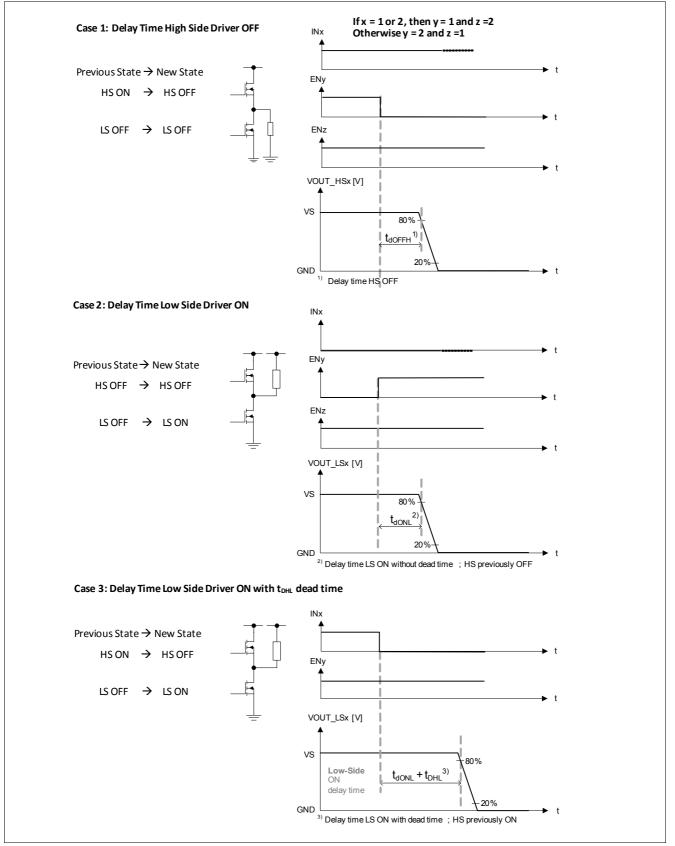
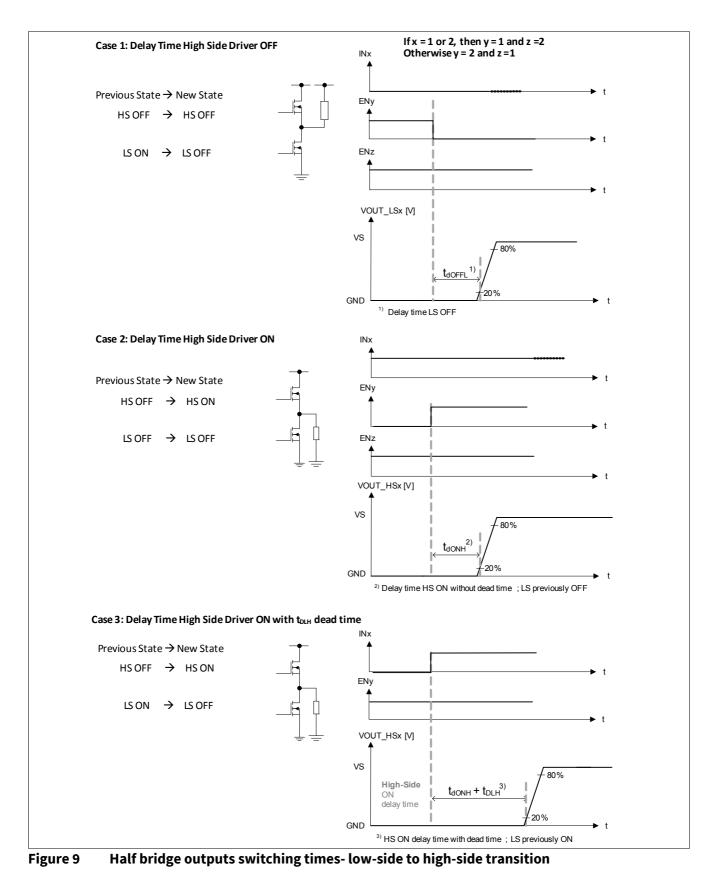


Figure 8 Half bridge outputs switching times - high-side to low-side transition





#### 6.3.3 Temperature monitoring and shutdown

Temperature sensors are integrated in the power stages. The temperature monitoring circuit compares the measured temperature to the shutdown threshold.



If one or more temperature sensors reach the shut-down temperature threshold, **all outputs are latched off**. All outputs remain deactivated as long as EN1 = 1 or EN2 = 1.

To resume normal functionality of the power switch (in the event the overtemperature condition disappears or to verify if the failure still exists) the microcontroller shall:

- 1. clear the error flag by setting EN1 and EN2 to 0 (see Table 10)
- 2. set EN1 or EN2 to 1 in order to send the device from sleep mode back to normal mode

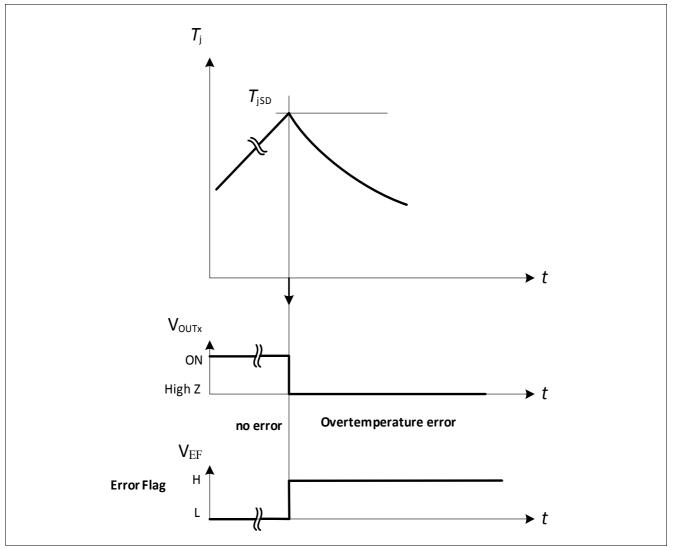


Figure 10 Overtemperature Behaviour



#### 6.3.4 VS Undervoltage Behaviour

If the supply voltage decreases to the undervoltage switch-off threshold,  $V_{UV OFF}$ , then all output switches are switched off, and the error flag EF is set to High (error detection). If  $V_S$  rises again and reaches the undervoltage switch-on threshold,  $V_{UV ON}$ , the power-stages are automatically reactivated according to ENx and INx. Refer to **Figure 11** 

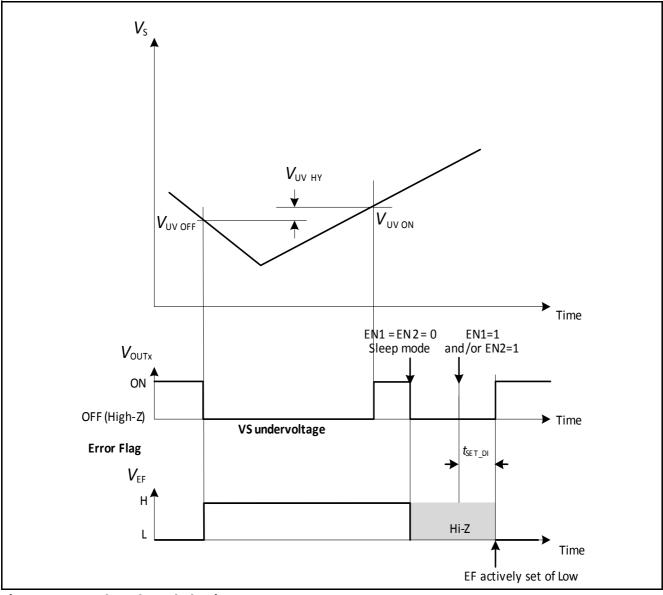


Figure 11 Undervoltage behaviour



#### 6.3.5 VS Overvoltage Behaviour

If the supply voltage increases beyond the overvoltage switch threshold,  $V_{\text{OV OFF}}$ , then all output switches are switched off and EF is set High, indicating an overvoltage condition. If  $V_{\text{S}}$  decreases again and reaches the overvoltage switch-on threshold,  $V_{\text{OV ON}}$ , then the power-stages are automatically reactivated according to ENx and INx. Refer to Figure 12.

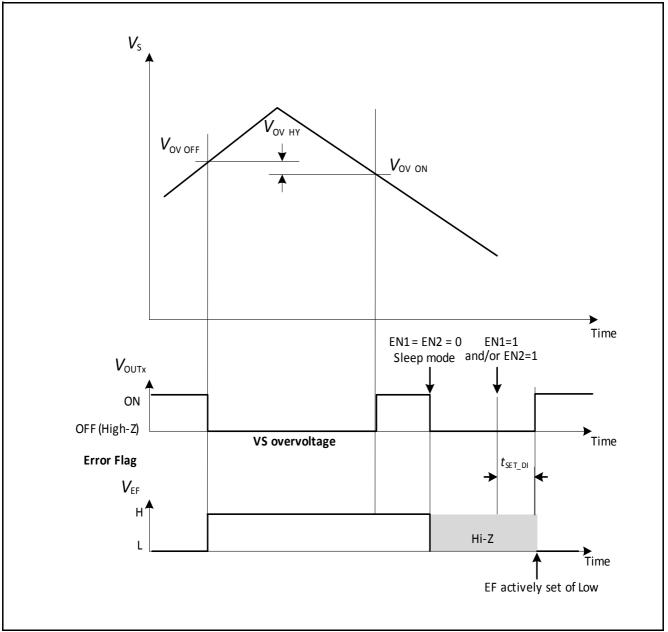


Figure 12 Overvoltage behaviour

#### 6.3.6 V<sub>DD</sub> Undervoltage

In the event the  $V_{DD}$  logic supply decreases below the undervoltage threshold,  $V_{DD_{POFFR}}$ , the TLE94004EP will enter reset. EF is set to high impedance during a  $V_{DD}$  undervoltage event.

The digital block will be initialized and the output stages are switched off to High impedance. The undervoltage reset is released once  $V_{DD}$  voltage levels are above the undervoltage threshold,  $V_{DD POR}$ .



# 7 Application Information

Note: The following simplified application examples are given as a hint for the implementation of the device only and shall not be regarded as a description or warranty of a certain functionality, condition or quality of the device. The function of the described circuits must be verified in the real application.

#### 7.1 Application Diagram

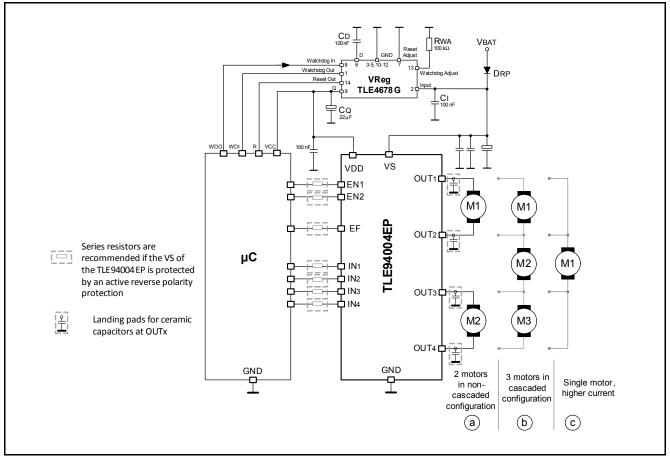


Figure 13 Application Example for DC-motor loads



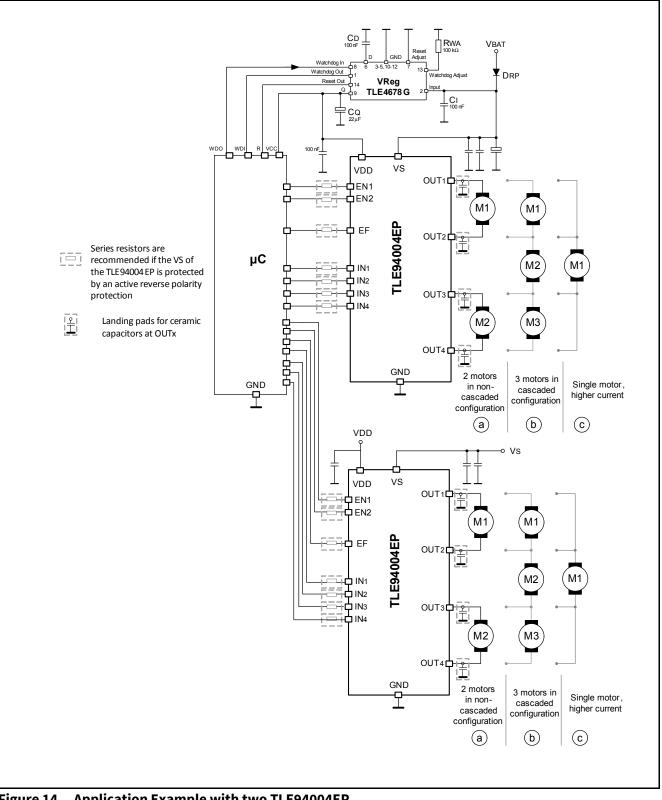


Figure 14 Application Example with two TLE94004EP



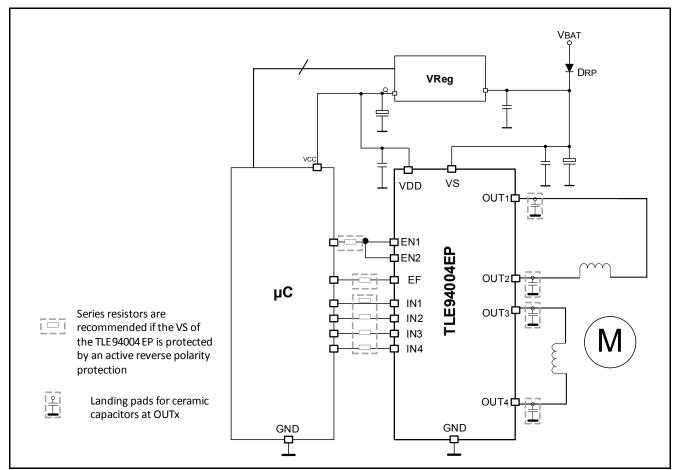


Figure 15 Application Example with TLE94004EP driving a bipolar transistor in voltage mode control

#### Notes on the application example

- 1. Series resistors between the microcontroller and the signal pins of the TLE94004EP are recommended if an active reverse polarity protection (MOSFET) is used to protect the VS pin. These resistors limit the current between the microcontroller and the device during negative transients on VBAT (e.g. ISO/TR 7637 pulse 1)
- 2. Landing pads for ceramic capacitors at the outputs of the TLE94004EP as close as possible to the connectors are recommended (the ceramic capacitors are not populated if unused). These ceramic capacitors can be mounted if a higher performance in term of ESD capability is required.
- 3. The electrolytic capacitor at the VS pin should be dimensioned in order to prevent the VS voltage from exceeding the absolute maximum rating. PWM operation with a too low capacitance can lead to a VS voltage overshoot, which results in a VS overvoltage detection.
- 4. Unused outputs are recommended to be left unconnected (open) in the application. If unused output pins are routed to an external connector which leaves the PCB, then these outputs should have provision for a zero ohm jumper (depopulated if unused) or ESD protection. In other words, unused pins should be treated like used pins.
- 5. Place bypass ceramic capacitors as close as possible to the VS pins, with shortest connections the GND pins and GND layer, for best EMC performance



#### 7.2 Thermal application information

 $Ta = -40^{\circ}C$ , Ch1 to Ch4 are dissipating a total of 0.8W (0.2W each).

Ta = 85°C, Ch1 to Ch4 are dissipating a total of 0.54W (0.135W each).

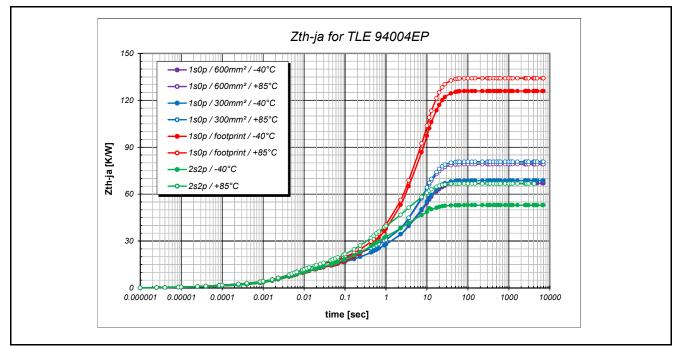


Figure 16 ZthJA Curve for different PCB setups

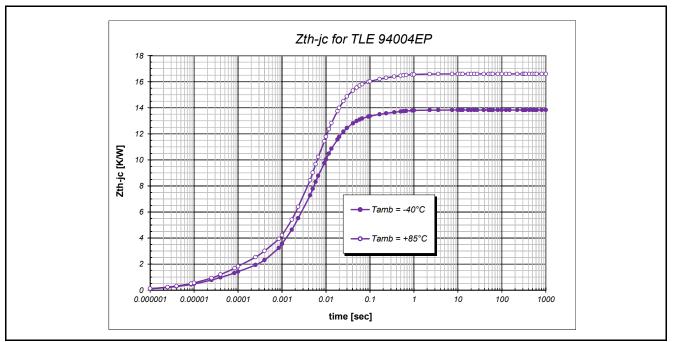


Figure 17 ZthJC Curve



#### **Package Outlines**



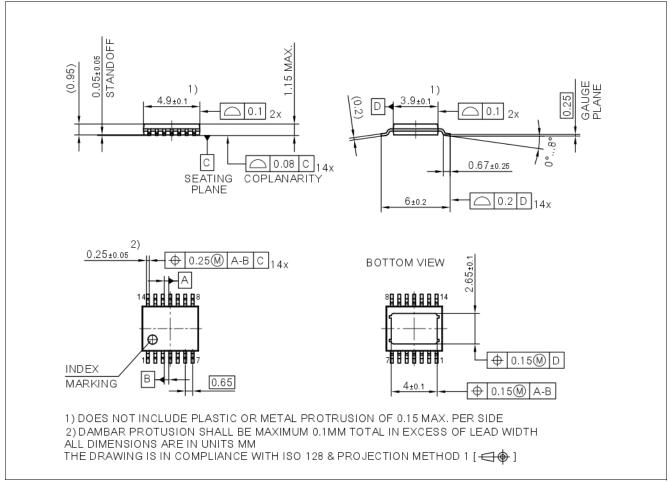


Figure 18 PG-TSDSO-14 (Plastic Green - Dual Small Outline Package)

#### **Green Product (RoHS compliant)**

To meet the world-wide customer requirements for environmentally friendly products and to be compliant with government regulations the device is available as a green product. Green products are RoHS-Compliant (i.e lead-free finish on leads and suitable for Pb-free soldering according to IPC/JEDEC J-STD-020).



**Revision History** 

# 9 Revision History

Revision	Date	Changes
1.0	2017-12-07	Initial release

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